

### IEC QUALITY ASSESSMENT SYSTEM (IECQ)

For rules and details of the IECQ visit www.iecq.org

# Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 21.0003-04
CB Certificate No.: 50600709 ITL

Schedule Number: IECQ-L ULTW 21.0003-04-S Rev No.: 1 Revision Date: 2025/10/11 Page 1 of 2

## **Appendix-1 (50600709 ITL) Schedule of Scope to Certificate of Approval**

Test Items		
ANSI/ESDA/JEDEC JS-001 AEC-Q100-002 MIL-STD-883L method 3015.9 AEC-Q101-001-REV-A GJB 548C 方法 3015.1		
ANSI/ESDA/JEDEC JS-002 AEC-Q100-011 AEC-Q101-005		
JEDEC JESD78F AEC-Q100-004		
HZJF-WI-FA-009		
HZJF-WI-FA-005		
HZJF-WI-FA-006		
HZJF-WI-FA-007		
HZIF-WI-FA-019		
HZJF-WI-FA-012		
HZJF-WI-FA-025		

This schedule is only valid in conjunction with the referenced Certificate of Approval
This approval and any schedule(s) may only be reproduced in full.
This approval is not transferable and remains the property of the issuing body.
The Status and authenticity of this approval and any schedule(s) may be verified by visiting the
Official IECQ Website. <a href="www.iecq.org">www.iecq.org</a>





#### **IEC QUALITY ASSESSMENT SYSTEM (IECQ)**

For rules and details of the IECQ visit www.iecq.org

# Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 21.0003-04
CB Certificate No.: 50600709 ITL

Schedule Number: IECQ-L ULTW 21.0003-04-S Rev No.: 1 Revision Date: 2025/10/11 Page 2 of 2

IV cure tracer 曲线追踪仪测试	HZJF-WI-FA-010
Probe 射频探针	HZJF-WI-FA-013
Reactive-Ion Etching RIE 气体蚀刻	HZJF-WI-FA-020
Grinder 研磨	HZJF-WI-FA-018
SecondaryElectron Microscope (SEM) 扫描电镜-8100	HZJF-WI-FA-016

	Paul	Tang	
Technical Reviewer of DQS:		0	Date: 10/11/2025

